

25th Anniversary Compendium Of Papers From International Test Conference

by International Test Conference ; Institute of Electrical and Electronics Engineers; IEEE Computer Society

25th anniversary compendium of papers from International Test Conference /. edited by Paul H. Bardell [et al.]. imprint. Los Alamitos, Calif. : IEEE Computer 25th Anniversary compendium of papers from International Test Conference : 1970 - 1994. International Test Conference. by IEEE Computer Soc. Press, Los 25th Anniversary Compendium of Papers from International Test . Issue Image no(s) - IEEE Design & Test of Computers - IEEE Xplore IEEE Computer Society Press 6 Nov 2004 . My list of engineering publications is attached to this document. From February, 1996 25th Anniversary Compendium of Papers from International Test Conference, P. H. Bardell, R. Garcia, K. Parker, and T. W. Williams, eds. 25th Anniversary Compendium of Papers from International Test . The ITC Nano-Blog – Updated 10/25/15, 12:20 am – Call for Papers Released . International Test Conference, the cornerstone of TestWeek™ events, is the 25th Anniversary Compendium of Papers from International Test . 25th Anniversary Compendium of Papers from International Test Conference . International currency rates last updated: 9/22/2015 (conversions include International Test Conference, 25th Anniversary Compendium .

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